Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/811,741	LAM ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED					
Class	Subclass	Date	Examiner		
29	417 603.09 603.15 603.16 603.18	12/29/2005	PK		
360	121 125 126	12/29/2005	PK		
	316 317	<b>V</b>			
451	4,51	12/30/2005	PK		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Reviewed Parent Application 10/097,294 (US PAT. 6,950,289)	12/29/2005	PK		
Text Search EAST/NPL (IEEE)	12/30/2005	PK		